

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Vuthe Siek	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2005/0066242 A1	03-2005	Wang et al.	714/700
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lin et al., "High-Frequency, At-Speed Scan Testing," IEEE, October 2003, pp. 17-25
	V	Wang et al., "DS0LFSR: A BIST TPG for Low Switching Activity," IEEE, July 2002, pp. 842-851
	W	Heragu et al., "FACTS: Fault Coverage Estimation by Test Vector Sampling," IEEE, 1994, pp. 266-271.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.